Supplementary Information

Photodynamic Response of a Solution Processed Organolead Halide Photodetector

Vishwa Bhatt¹, Kavita Pandey¹, Sanjeev. K Gupta², Yogesh Sonvane³, Pankaj Yadav^{4*}, Manoj Kumar^{1*}

¹School of Technology, Pandit Deendayal Petroleum University, Gandhinagar – 382007, India

²Computational Materials and Nanoscience Group, Department of Physics and Electronics, St.

Xavier's College, Ahmedabad – 380009, India

³Advaced Materials Lab, Department of Applied Physics, S. V. National Institute of Technology,

Surat – 395007, India

⁴Department of Electrical Engineering, Incheon National University, Incheon – 406772, Korea

*Corresponding author: <u>manoj.kspv@gmail.com</u>

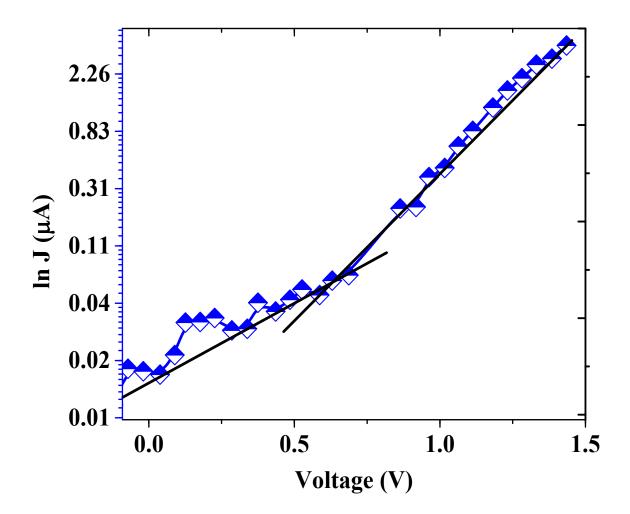


Figure S1. The plot of current against the applied voltage to calculate the ideality factor from the slopes of the line

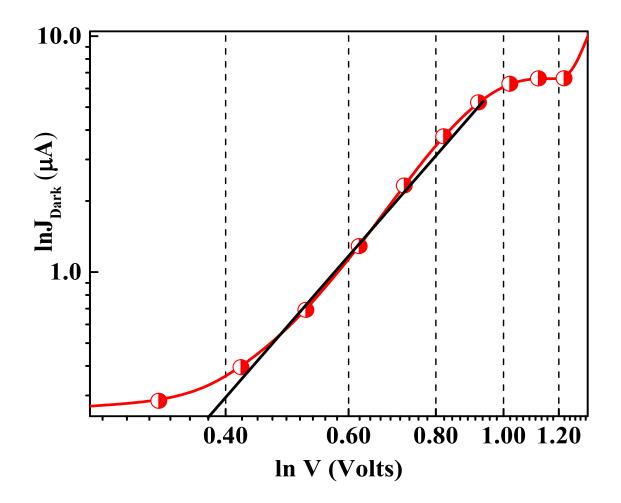


Figure S2. The plot of dark current against the applied voltage to calculate the ideality factor at the higher potential

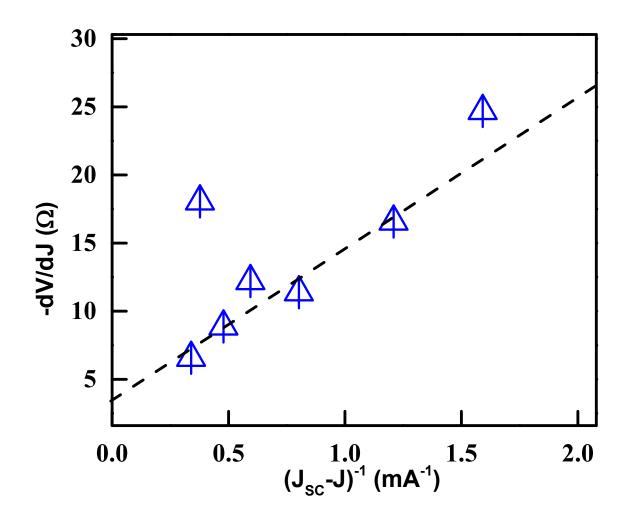


Figure S3. The plot of -dV/dJ versus $(J_{SC}-J)^{-1}$ with the linear fitting curves

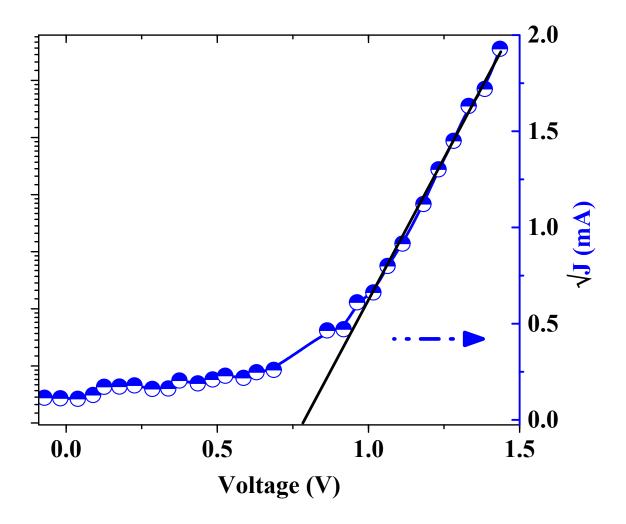


Figure S4. Extraction of mobility value by using Mott-Gurney relation

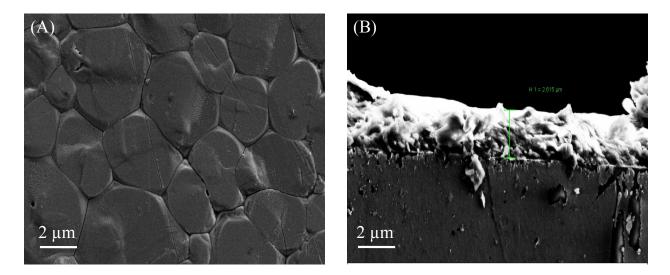


Figure S5. SEM images of the perovskite thin film at high magnification and cross-sectional view

The FESEM micrographs of $CH_3NH_3PbI_3$ thin films on FTO substrate are shown in Figure S5 (A and B). The FESEM micrograph of deposited film (Fig. S5A) confirms that the film is uniform, and the grains are cube-shaped. The thickness of the deposited perovskite film can be measured using the FESEM in a cross sectional view shown in Figure S5 and film thickness was found to be ~3 μ m.